



APSQ User WS@University of Oxford, 22 - 24 May 2024

A Lightweight Algorithm for Modelling Radiation Damage effects in the MC events for HL-LHC experiments

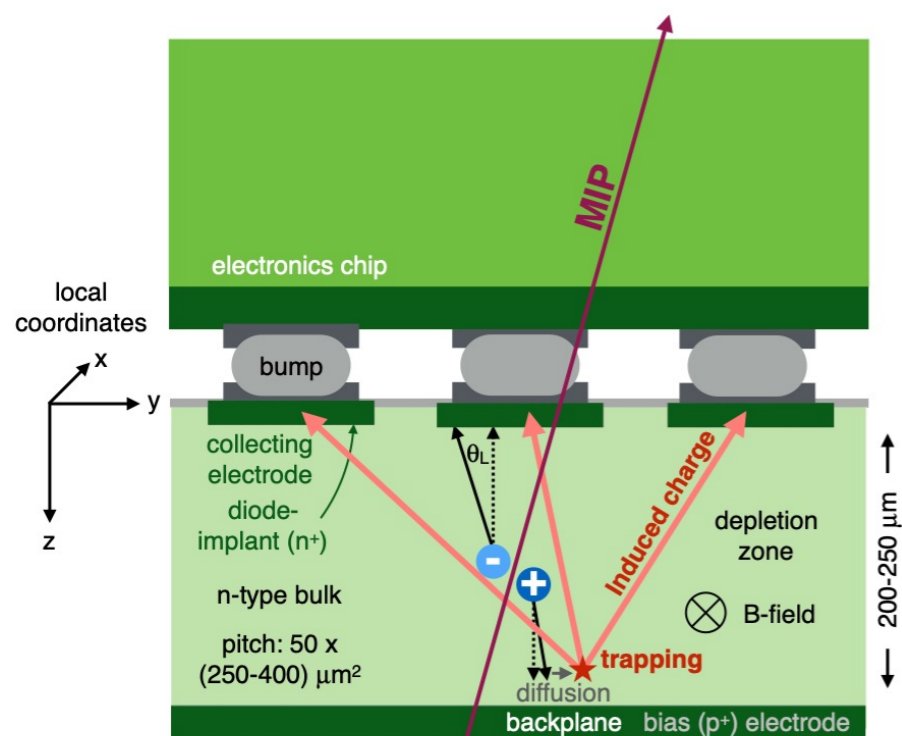
**Marco Bomben & Keerthi Nakkalil
APC & Université de Paris**



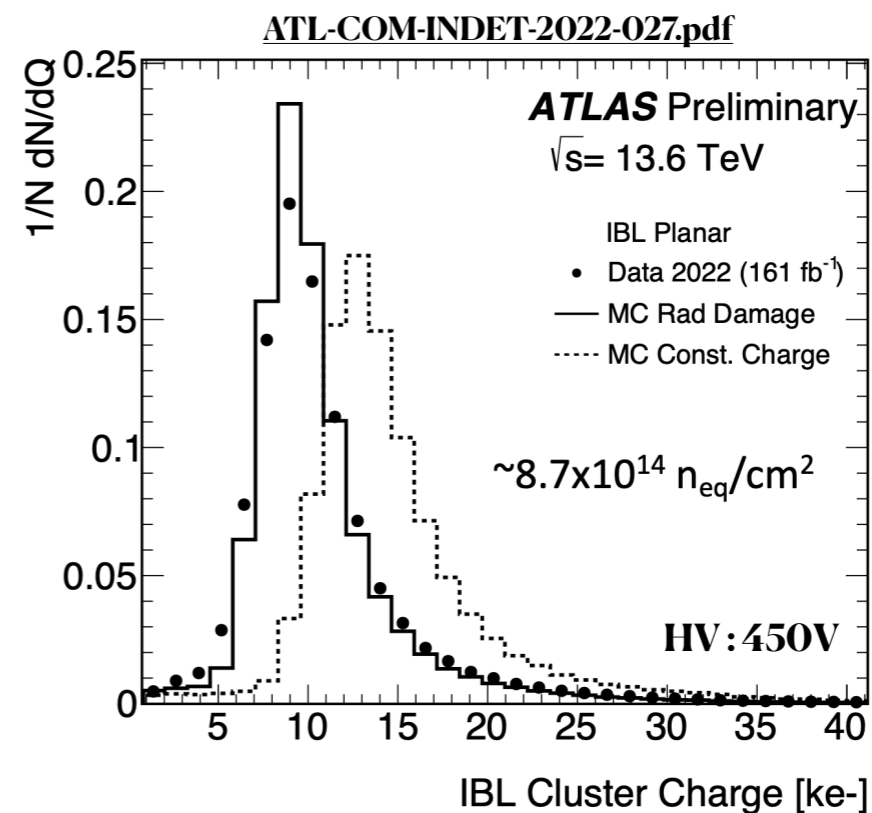
Radiation damage modelling : ATLAS approach

Run2 and Run3 strategy

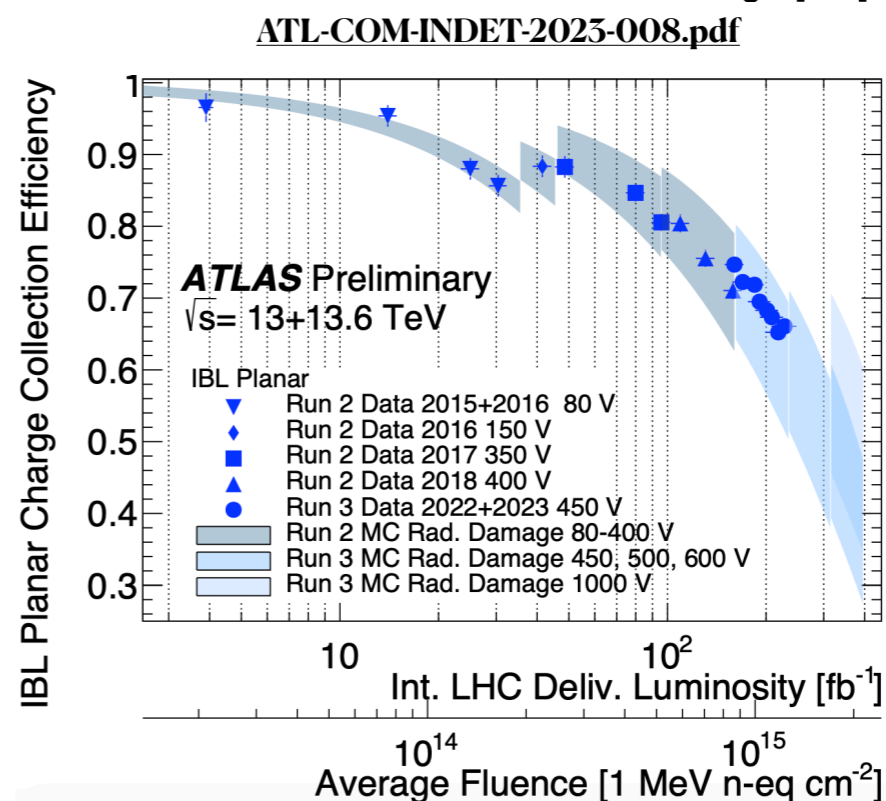
- Current strategy : Evaluate final position and induced signal of group of carriers in MC
- Inputs:
 - ◆ Precise electric field simulation (TCAD) to take into account radiation damage effects
 - ◆ Weighting potential (TCAD)
 - ◆ Trapping rates (literature)



<https://iopscience.iop.org/article/10.1088/1748-0221/14/06/P06012>



Most Probable Values match at 1% level!

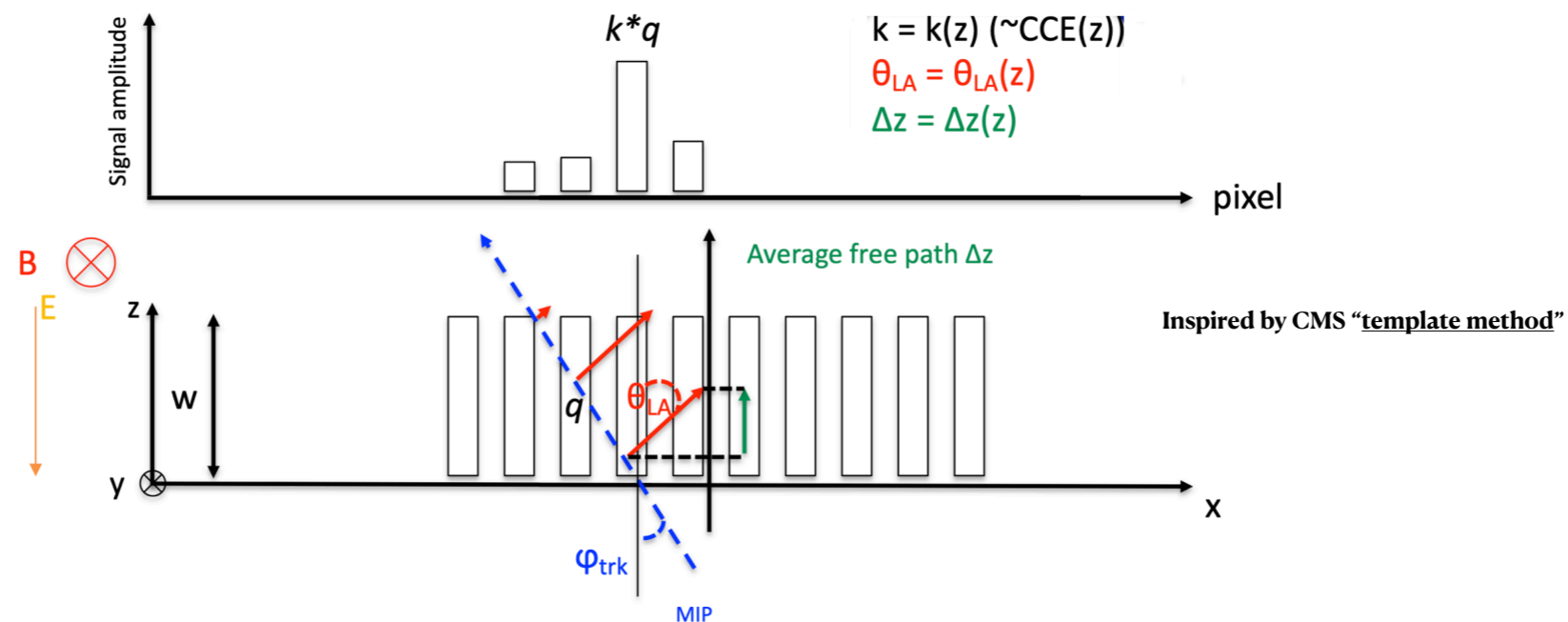


Excellent agreement over almost two order of magnitudes of fluence!

Radiation damage modelling : ATLAS approach

HL-LHC strategy

- HL-LHC : ATLAS/CMS pixel detectors exposed to unprecedented levels of radiation damage
 - ◆ Peak luminosity: $1 \times 10^{34} \rightarrow 5 - 7 \times 10^{34} \text{ cm}^{-2} \text{ s}^{-1}$
 - ◆ Average collisions/BC: $\sim 30 \rightarrow \sim 200$
 - ◆ Integrated luminosity: $350 \rightarrow 4000/\text{fb}$
- Expected increase of particles density and rates in HL-LHC -> need for a faster algorithm
 - ◆ New strategy is planned : charge reweighing from look-up tables (LUTs)



- Idea : For each simulated charge q at depth z find in **which pixel it will end up**, by how much (k) **the signal will be reduced**
 - ◆ Goal: Simulated pixels in MC is corrected using these information before digitisation -> correction scheme implemented using **Allpix-squared** ([doi:10.1016/j.nima.2018.06.020](https://doi.org/10.1016/j.nima.2018.06.020))

LUTs from Allpix-Squared

How to generate the LUTs

- Simulate **point** deposition using “scan” model ([DepositionPointCharge]) in AP2
 - ◆ Charge carrier deposition position change with every event, ensuring homogenous scanning of a single pixel cell
 - ◆ 125000 events simulated, deposit **1000** e-h pairs every 1um along x, y and 2 μm along z
 - ◆ Simulation for **100 μm** thick **planar** sensor at $4 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$ and **600 V**

- **Creation of CCE LUT**

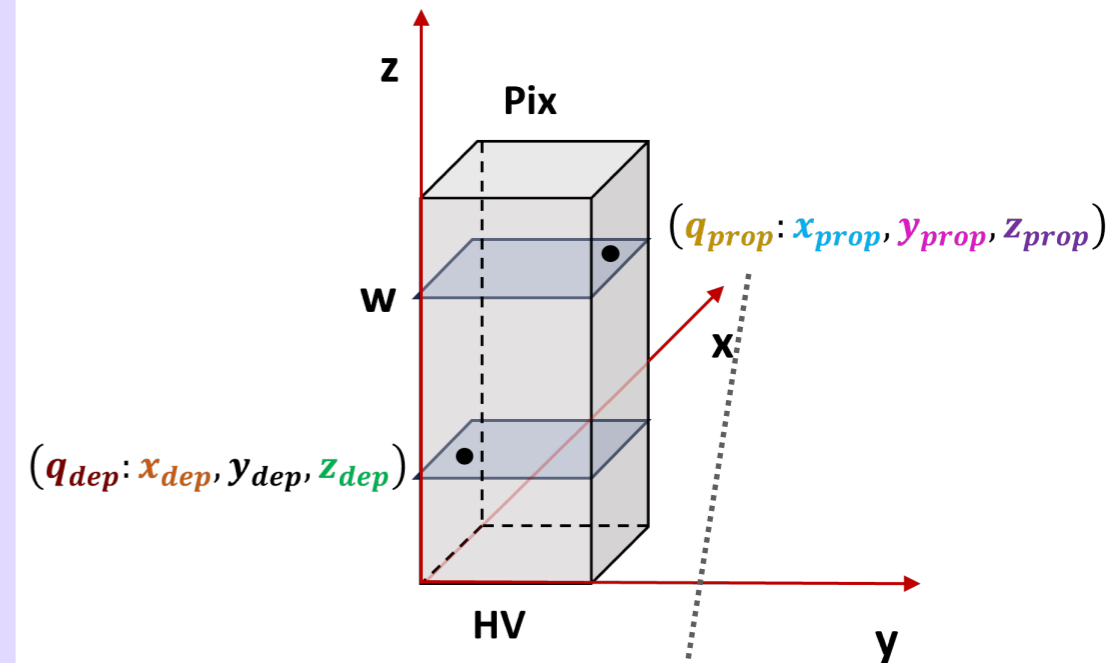
- ◆ CCE per event = (**max pixel charge**)/(q_{dep})
- ◆ CCE LUT obtained by taking the most probable CCE values (**MPV**) at various $x_{\text{dep}}, y_{\text{dep}}$ for each z_{dep}

- **Creation of tan(LA) LUT**

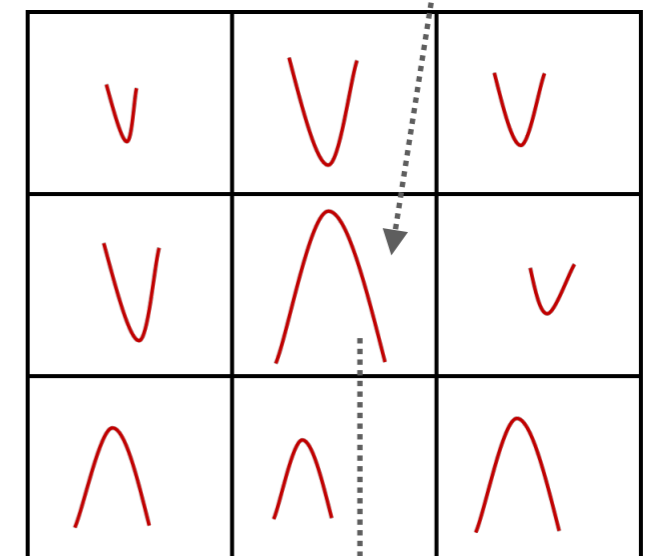
- ◆ Perform a pol1 fit to the distribution of electron drift for each z position (Δx vs. Δz) to extract the tanLA

- **Creation of delZ LUT**

- ◆ Perform a pol4 fit to distribution of $\Delta z(z_{\text{prop}} - z_{\text{dep}})$ vs z to fill Δz LUT



3x3 induction matrix

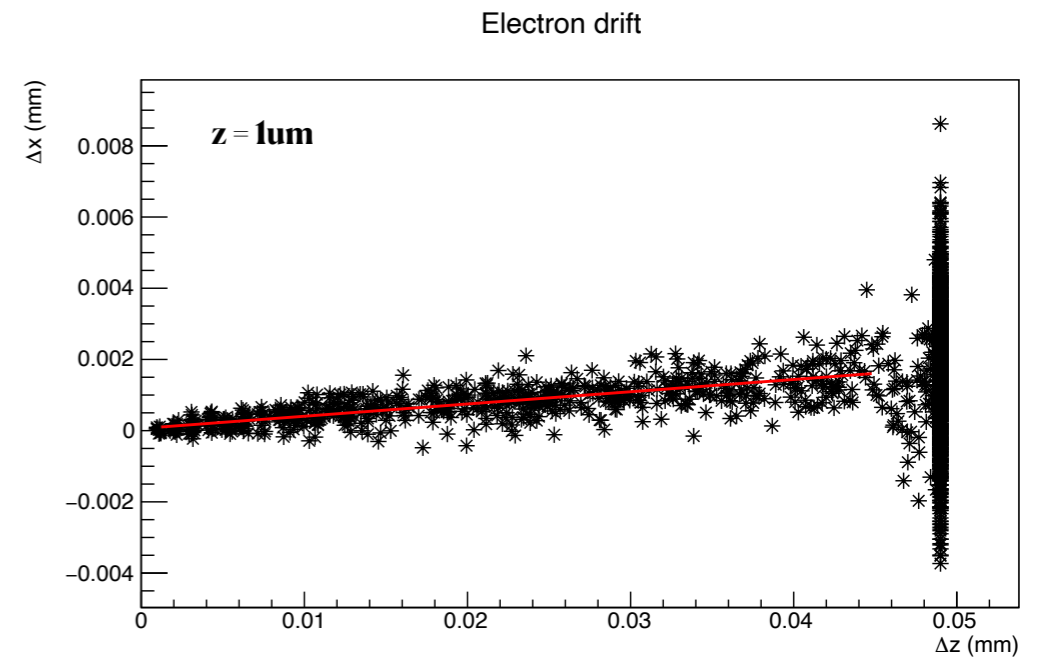


max pixel charge

LUTs from Allpix-Squared

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- **Creation of CCE LUT**

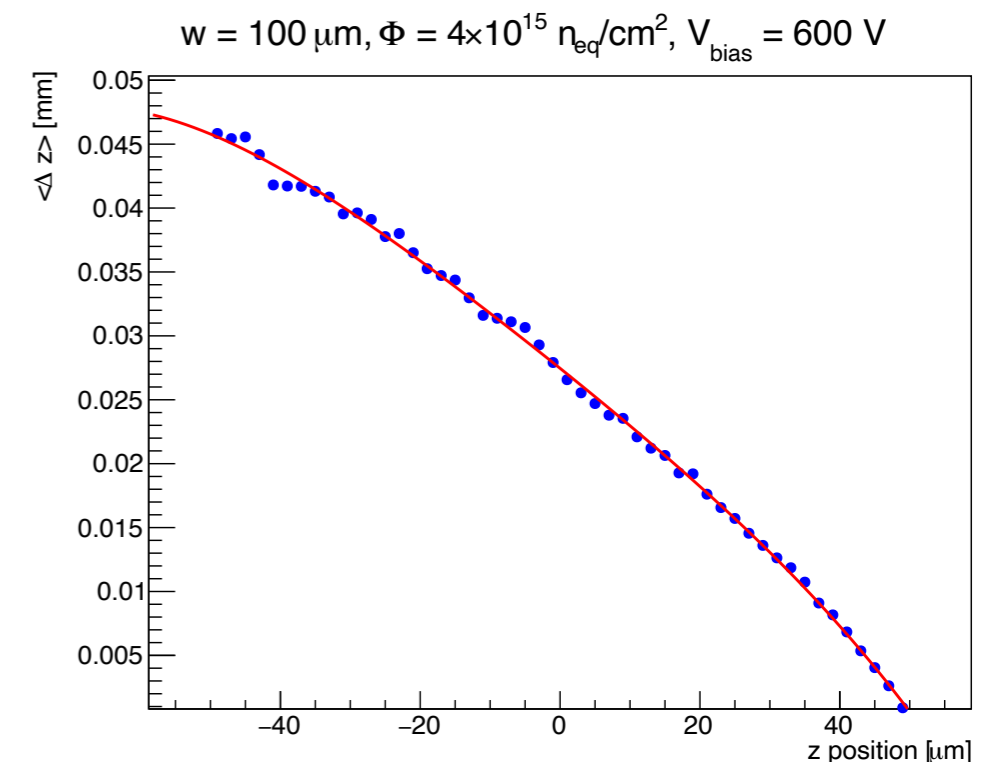
- ◆ CCE per event = (**max pixel charge**)/(q_{dep})
- ◆ CCE LUT obtained by taking the most probable CCE values (**MPV**) at various x_{dep} , y_{dep} for each z_{dep}

- **Creation of tan(LA) LUT**

- ◆ Perform a pol1 fit to the distribution of electron drift for each z position (Δx vs. Δz) to extract the tanLA

- **Creation of delZ LUT**

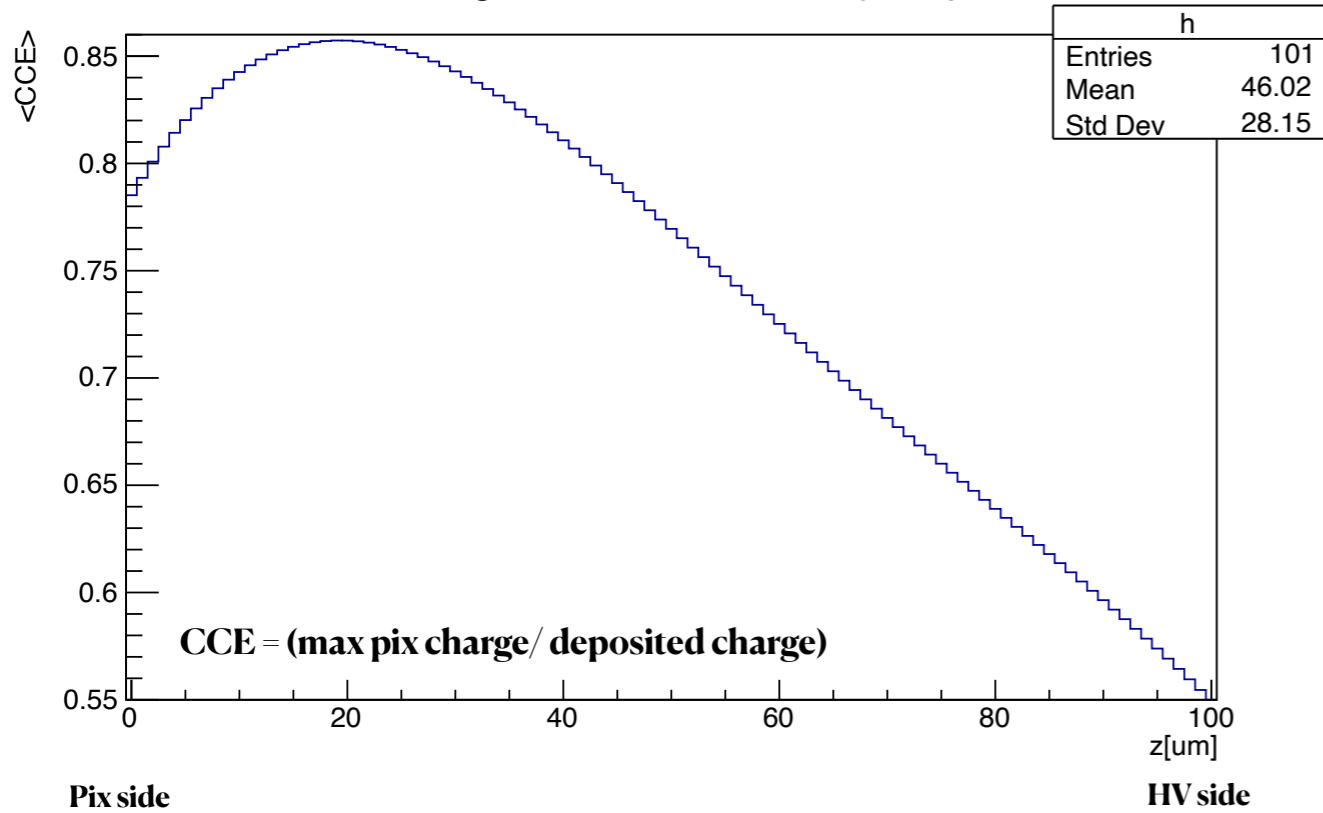
- ◆ Perform a pol4 fit to distribution of $\Delta z(z_{\text{prop}} - z_{\text{dep}})$ vs z to fill Δz LUT



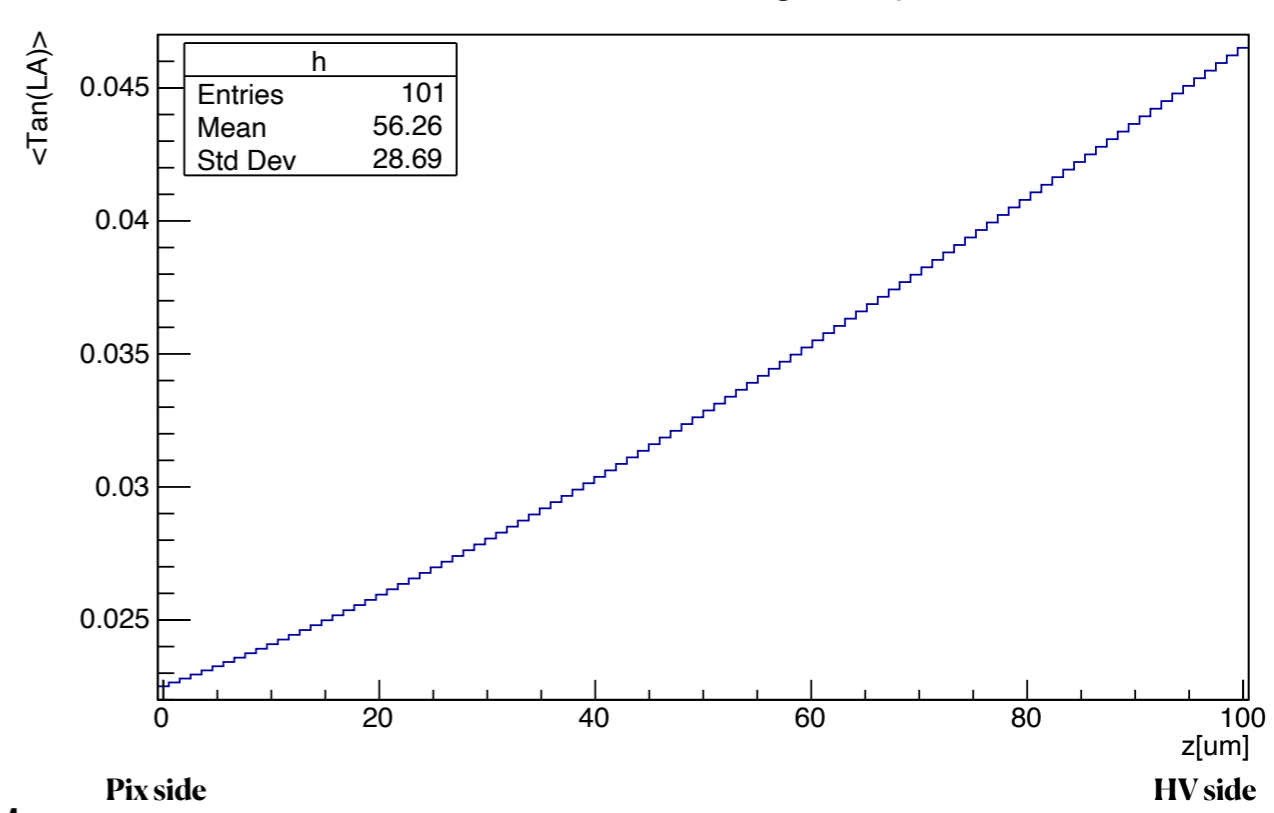
LUTs from Allpix-Squared

LUTs

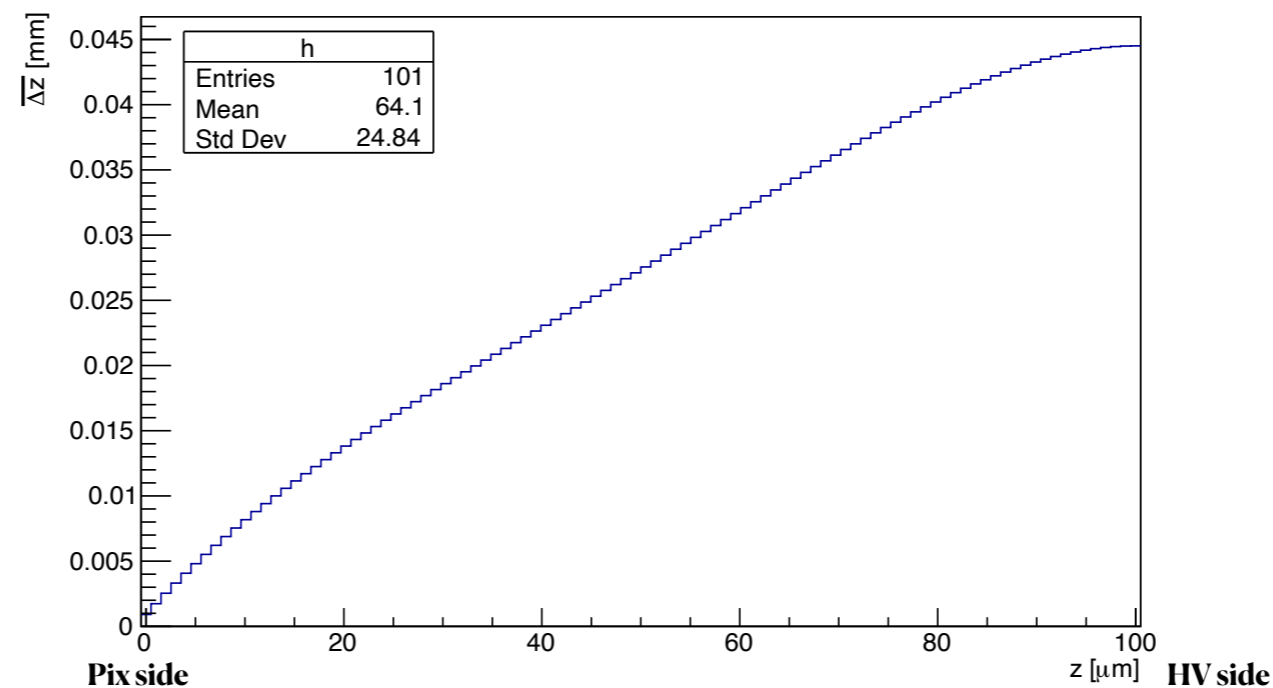
Charge collection efficiency map



Tan Lorentz Angle Map



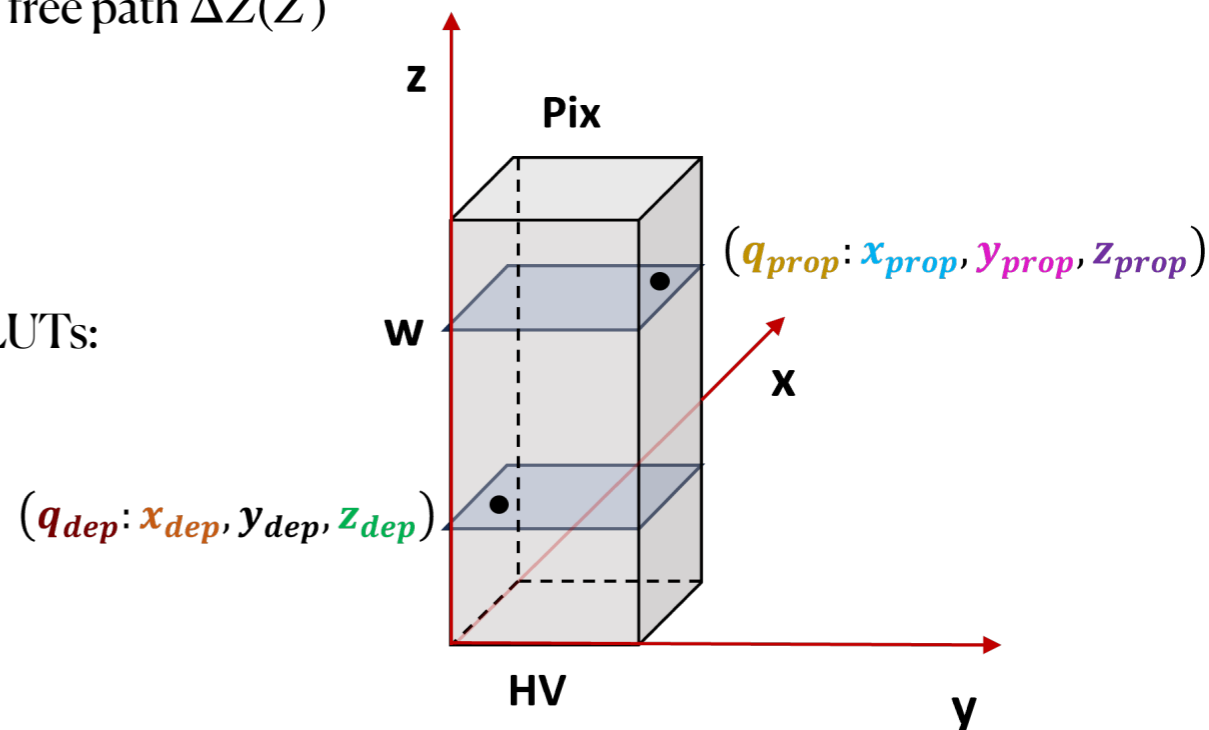
Δz Map



- Fluence = $4 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$
- Voltage = 600V
- Thickness = 100 μm
- Pitch = 50 $\mu\text{m} \times 50 \mu\text{m}$

Closure test

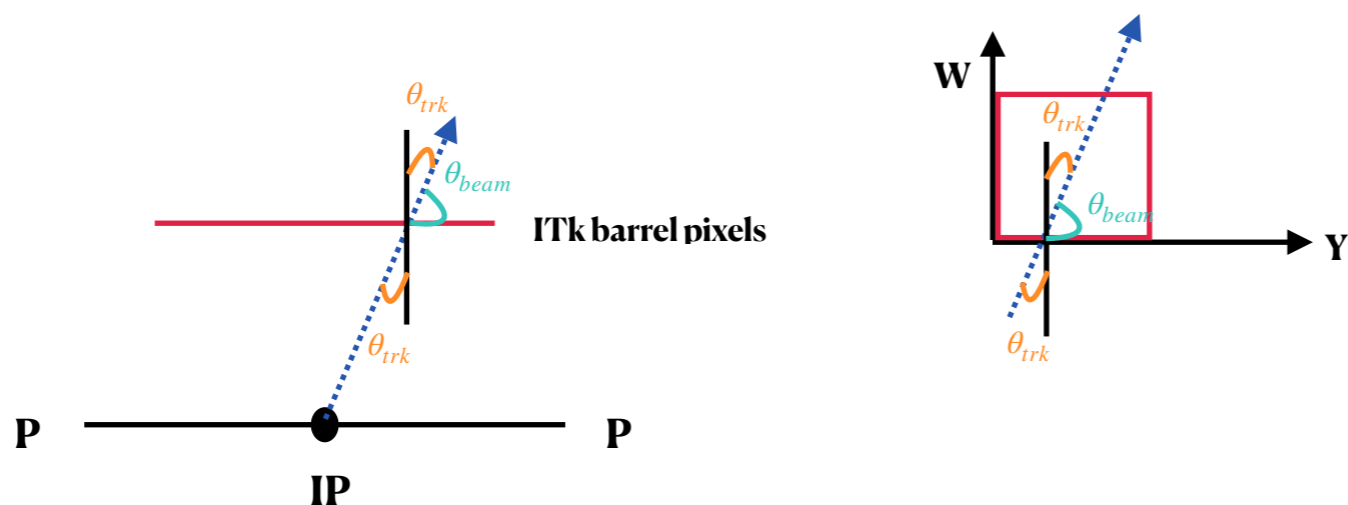
- Using AP2, we've estimated :
 - ✦ CCE (Z), average Lorentz angle deflection as a function Z , average free path $\Delta Z(Z)$
- Closure test to validate our approach :
 - ✦ Simulate charge deposition
 - ✦ Determine final position and fraction of induced charge using our LUTs:
 - ✦ $q_{prop} = CCE(z_{dep}) * q_{dep}(z_{dep})$
 - ✦ $z_{prop} = z_{dep} + \Delta z(z_{dep})$
 - ✦ $x_{prop} = x_{dep} + \tan(\theta_L)(z_{dep}) * \Delta z(z_{dep})$
 - ✦ Continue with transfer and digitisation steps
 - ✦ Compare the results at 3rd bullet with the ones obtained using the full chain that was used to produce the lookup table
- Developed a new module in Allpix-squared : LUTPropagator
- Performed closure tests with: point charge deposition, line charge deposition, **120 GeV Pions** using LUTs generated with the “scan” model of charge deposition
 - ✦ RD50 Dec'23 : [slides](#)
 - ✦ Allpix-Squared user workshop May23 : [slides](#)



Realistic simulation studies of ITk barrel pixels

Investigating P_t and η dependencies

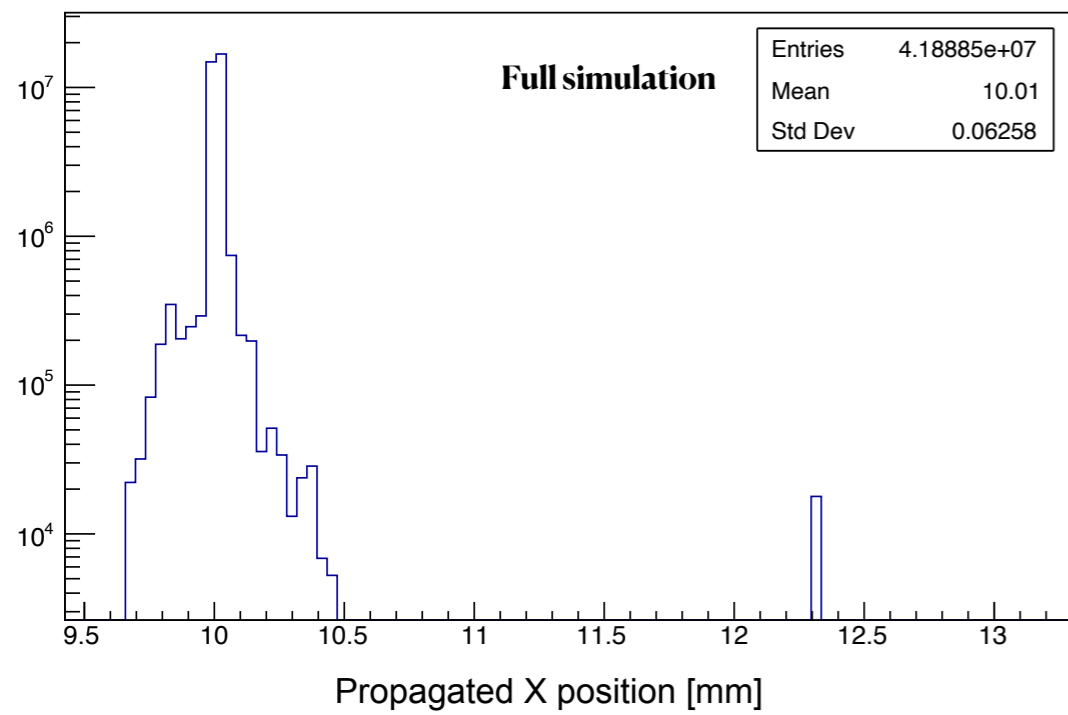
- Barrel layer ITk pixel modules tilted in the phi (**-0.25 rad**) to compensate for Lorentz angle deflection
- Studies with a **100um** thick planar pixel sensors (**50 μm x 50 μm**) at a fluence of **4x10¹⁵ neq/cm²** and **600V**
 - ✦ Pions (π^+) with **$P_t = 100 \text{ GeV}$, 10 GeV and 1 GeV** at $\eta = 0, 1$ and 1.4 ($\theta_{trk} = 0 \text{ rad}$, 0.866 rad and 1.088 rad respectively)
 - ✦ Each event has a single pion passing through the detector ; 1000 events simulated



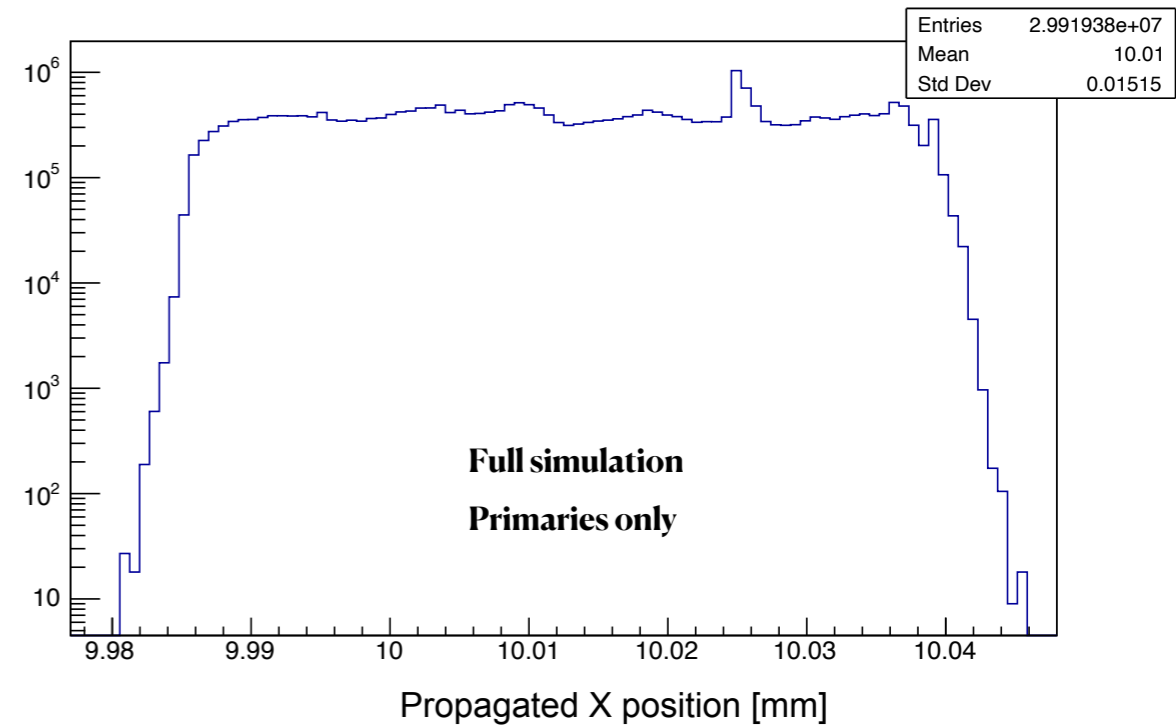
- Comparison of Allpix-Squared full simulation (FS) with LUTPropagator based simulations (LUT)
 - ✦ LUTPropagator module : Scale the charges using CCE LUT , propagate the carriers using **tan(LA)** and **ΔZ** LUTs
- Comparison variables : **propagated X position**, cluster size x, cluster size y, cluster charge

Propagated X Position

Pt = 100GeV, Eta = 1.4 ($\theta_{trk} = 1.088$ rad), -0.25 rad phi

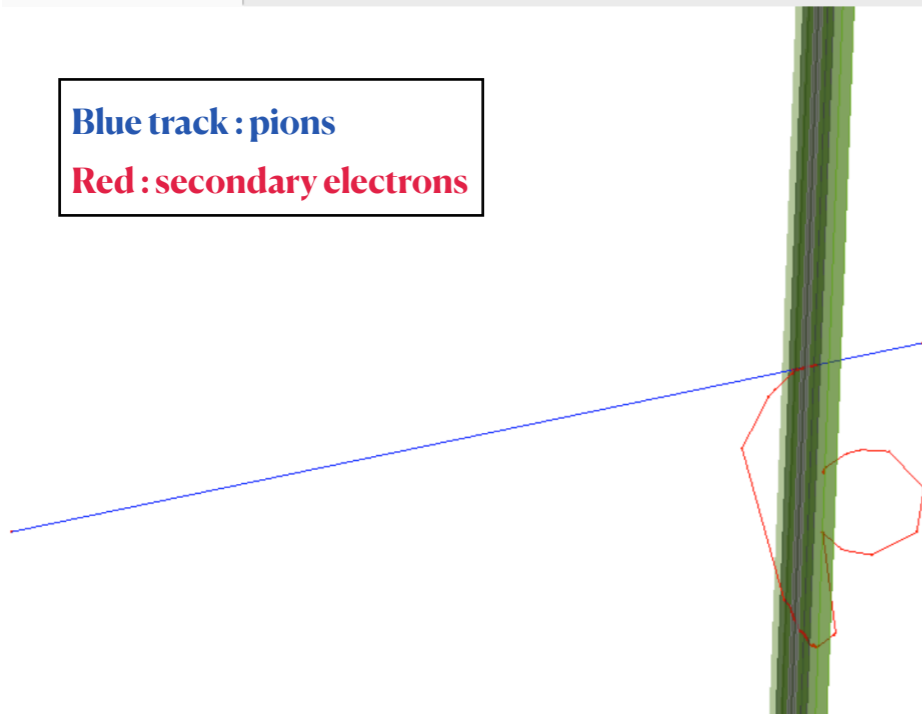


Filtering
secondaries
→

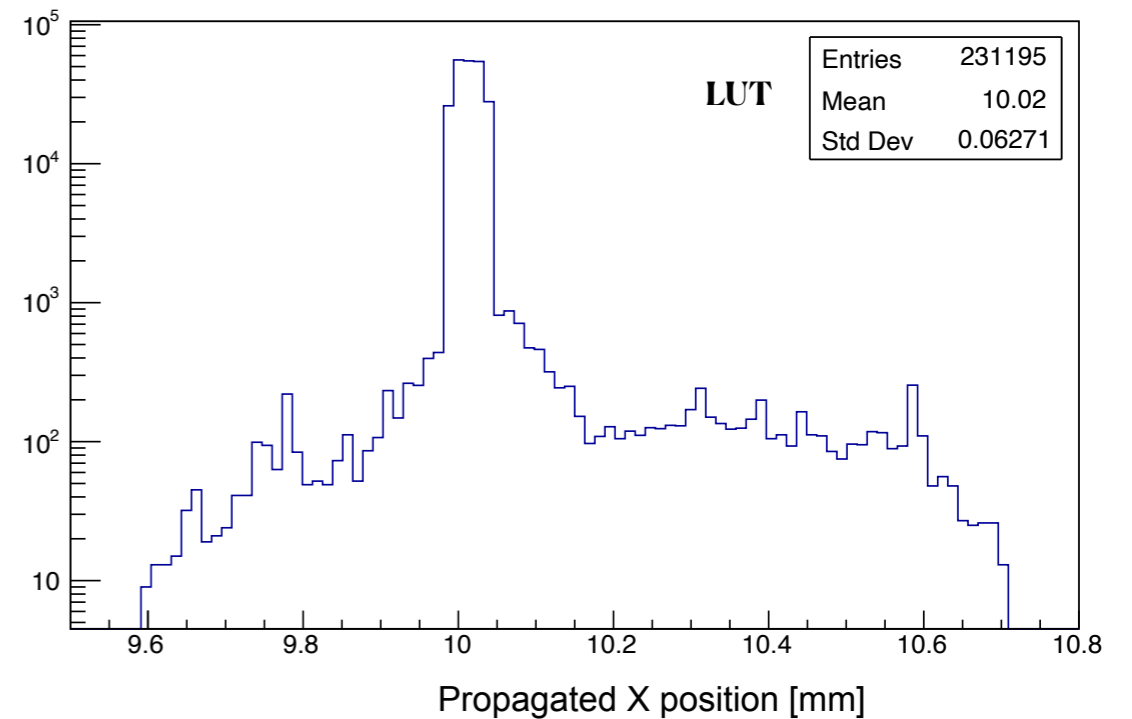


viewer-0 (OpenGLStoreQt) ✕

Blue track : pions
Red : secondary electrons



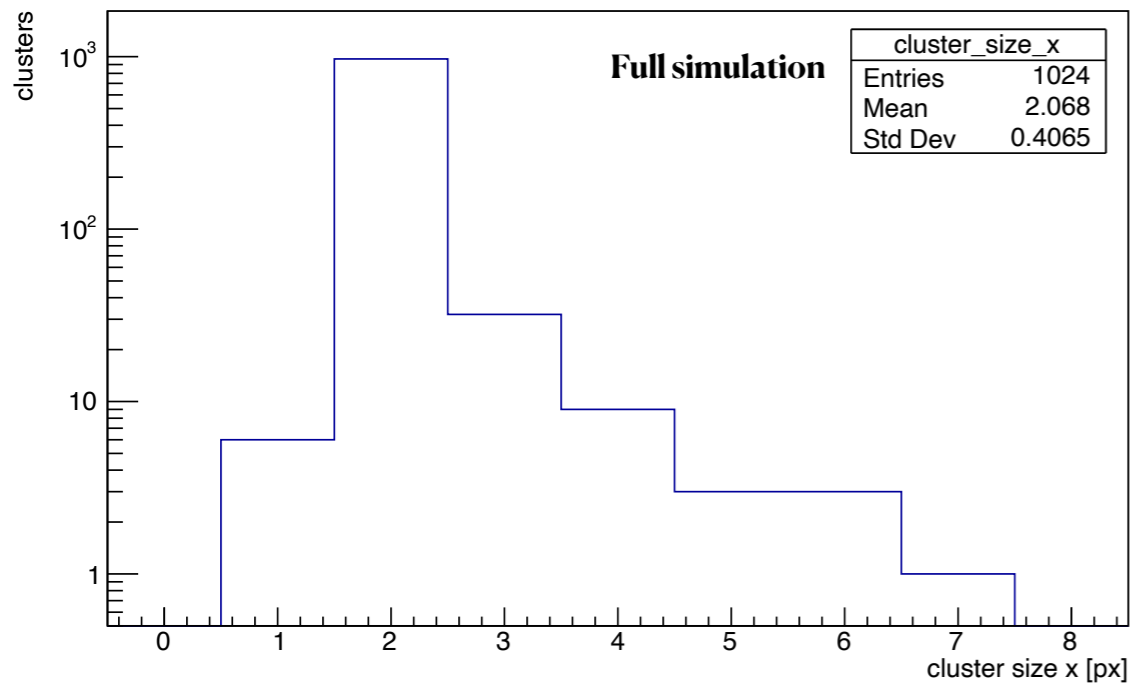
Diff = 7.4um
Diff/pitch = 14.8%



Cluster size - X,Y

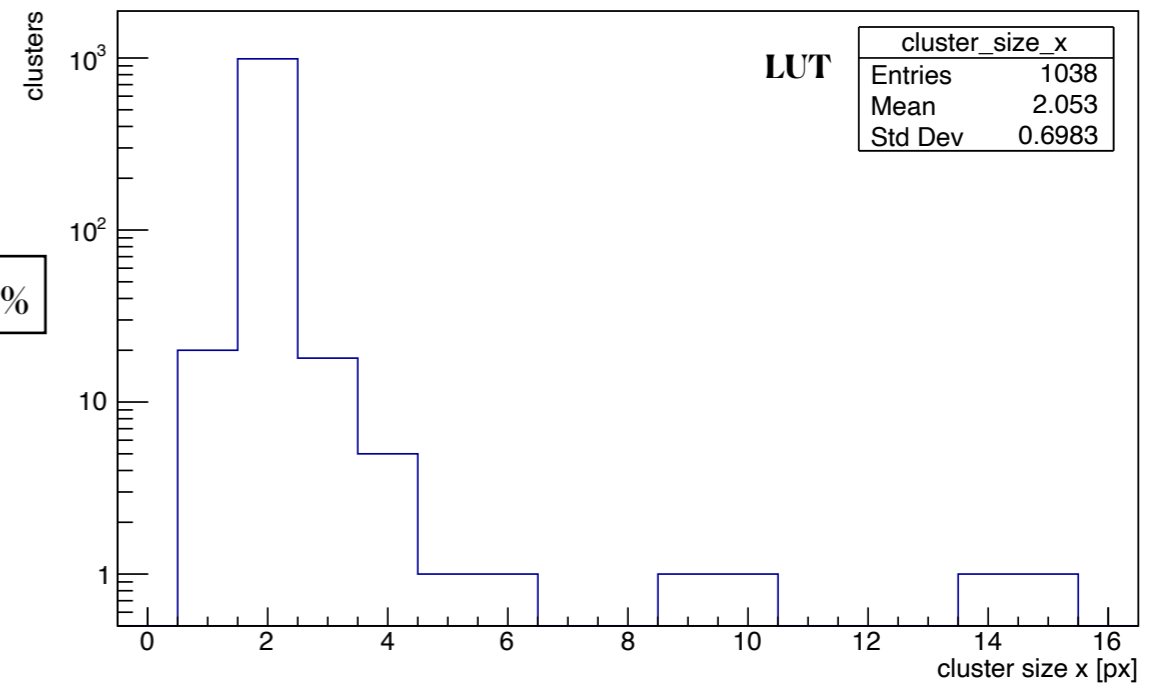
Pt = 100GeV, Eta = 1.4 ($\theta_{trk} = 1.088$ rad), -0.25 rad phi

Cluster size in X (detector1)

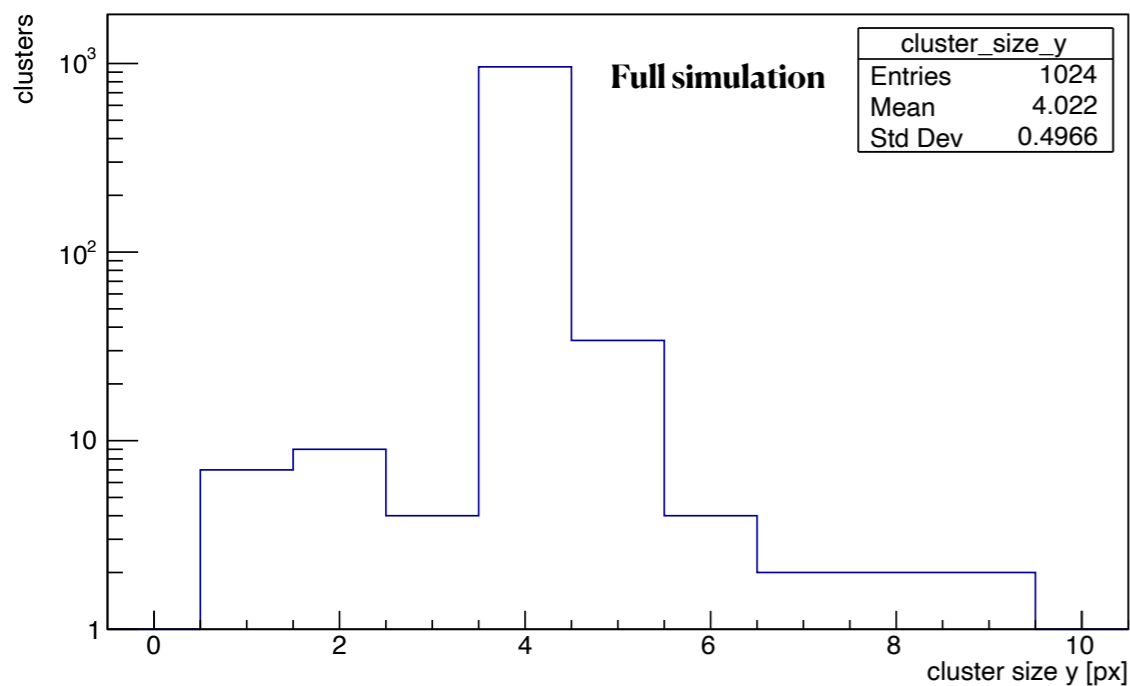


Rel err mean: 0.72%

Cluster size in X (detector1)

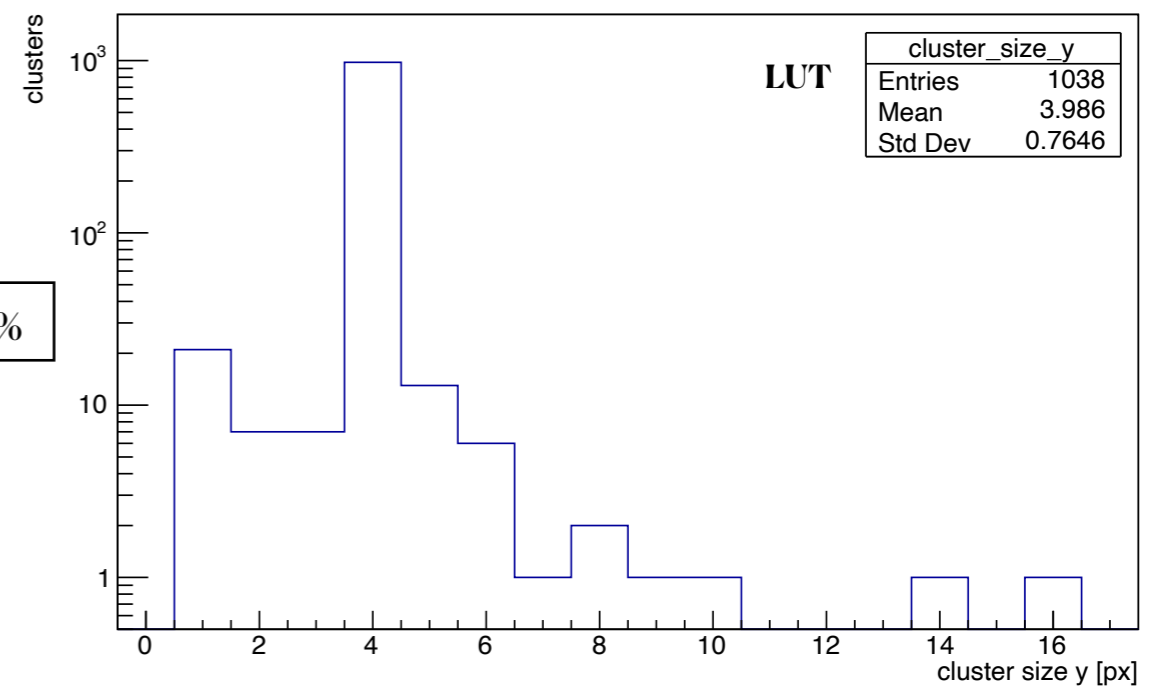


Cluster size in Y (detector1)



Rel err mean: 0.89%

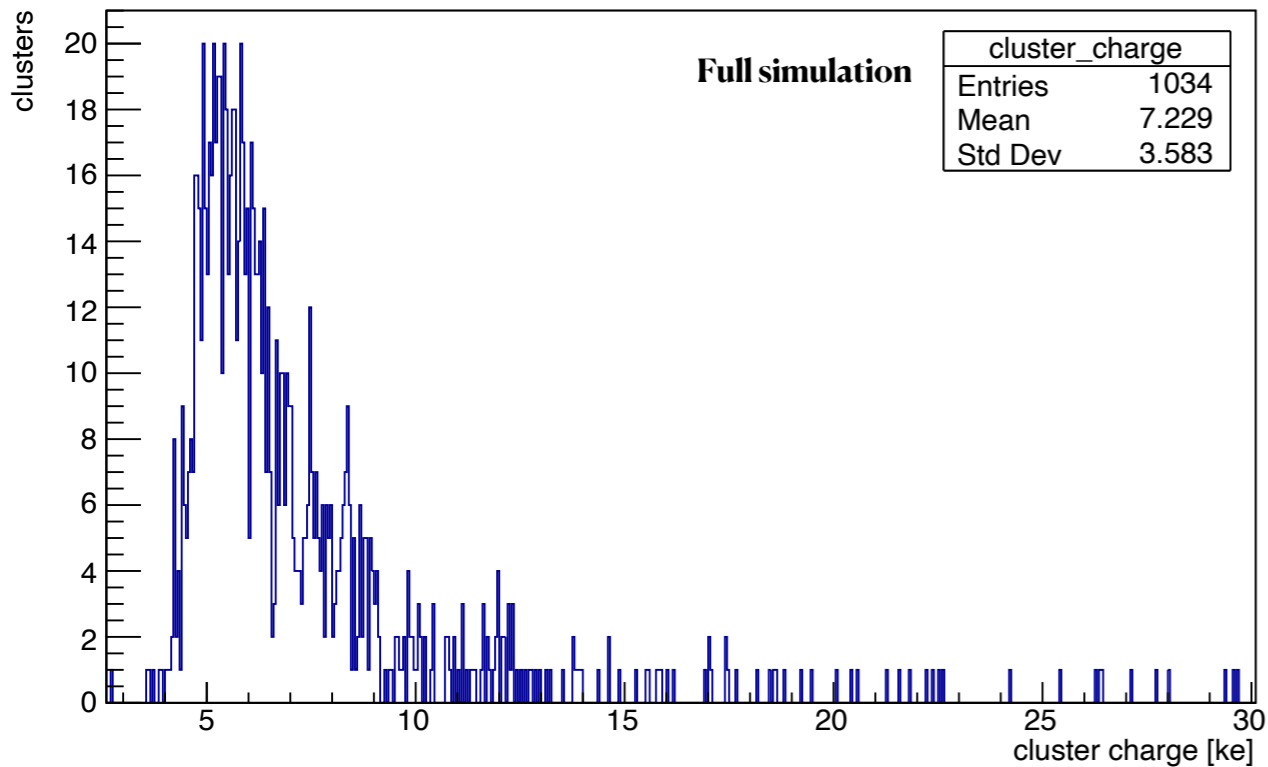
Cluster size in Y (detector1)



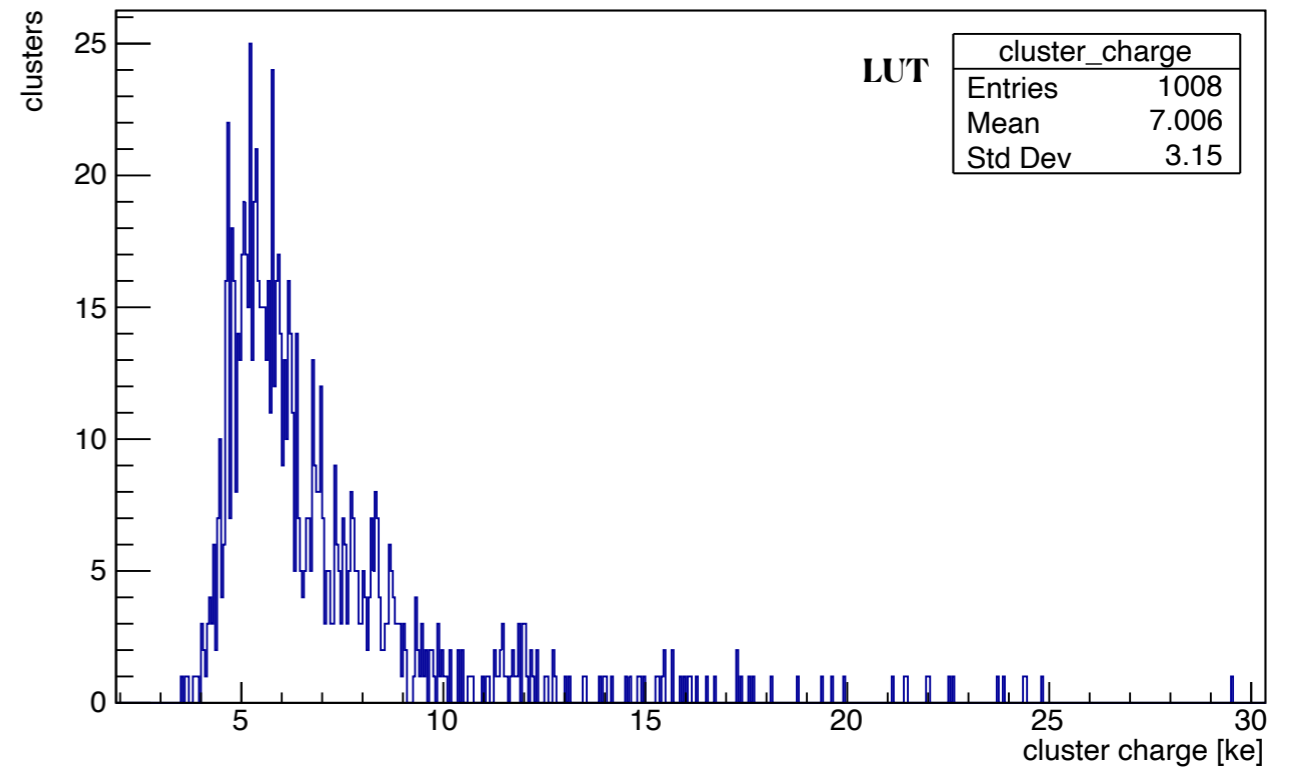
Cluster charge

Pt = 100GeV, Eta = 1.4 ($\theta_{trk} = 1.088$ rad), -0.25 rad phi

Cluster charge (detector1)



Cluster charge (detector1)



Rel err mean: 3.1%

- Results for Pt = 100GeV : backup slide #18 -29
- Results for Pt = 10 GeV : backup slides #30 - 41
- Results for Pt = 1GeV : backup slides #42 -53

Results of Pt = 1 GeV

Understanding trends

| Eta | Propagated X Position (mm) | | | Cluster Size Y(pix) | | | Cluster Size X(pix) | | | Cluster Charge (ke) | | |
|--------------------------------|----------------------------|---------|------------|---------------------|-------|---------|---------------------|-------|---------|---------------------|-------|---------|
| | FS | LUT | Diff/pitch | FS | LUT | Rel err | FS | LUT | Rel err | FS | LUT | Rel err |
| Normal incidence | 10 | 10 | 0 % | 1.1 | 1.032 | 6.2% | 1.099 | 1.041 | 5.3% | 6.957 | 6.741 | 3.1% |
| 1 (theta_trk = 0.866Rad) | 10.01 | 10.01 | 0 % | 3.027 | 3.001 | 0.86% | 1.186 | 1.404 | 18.38% | 10.25 | 10.54 | 2.8% |
| 1.4 (theta_trk = 1.088 Rad) | 10.0131 | 10.0152 | 4.2 % | 4.027 | 4.019 | 0.20% | 2.058 | 2.047 | 0.53% | 13.99 | 14.62 | 4.5% |

- Excellent agreement btw FS and LUT for PropagatedXPosition, relative difference < 5%
- Excellent agreement btw FS and LUT for cluster size y at different eta values
- Excellent agreement btw FS and LUT for cluster size X at different eta = 0 , 1.4, larger differences seen at eta = 1 for Pt = 100GeV and 10GeV (backup slides #20-21)
- Transverse cluster size (X) increases with higher eta values in both FS and LUT
 - ◆ Similar trend observed in ATLAS pixel data
 - ◆ Transverse cluster size \propto Longitudinal cluster size
- Good closure between FS and LUT for cluster charge at different eta values
 - ◆ Increasing eta -> particles incident at shallower angles, longer path length traversed in silicon, larger deposited charge , larger cluster charge

Cluster size X at $P_t = 100$ GeV

Investigating the trend

| Eta | Cluster size X (pix) | | |
|-----|------------------------|-------|---------|
| | FS | LUT | Rel err |
| 0 | 1.079 | 1.042 | 3.4% |
| 0.4 | 1.09 | 1.047 | 3.9% |
| 0.8 | 1.117 | 1.073 | 3.9% |
| 1 | 1.243 | 1.424 | 14.5% |
| 1.2 | 2.042 | 2.018 | 1.2% |
| 1.4 | 2.068 | 2.053 | 0.72% |

- Observed a discrepancy in the mean cluster size X between FS and LUT at $\eta = 1$
- Conducted a study by sampling finer η values around 1
- Excellent closure between FS and LUT seen for the new data points
 - ◆ Discrepancy in cluster size X is limited to a narrow region around $\eta = 1$

Beam divergence studies

Transverse cluster size, Pt = 120GeV, Eta = 1 ($\theta_{trk} = 0.866$ rad), -0.25 rad phi

- Beam divergences for simulations at eta = 1 were increased by ± 10 mrad \rightarrow eta : [0.99, 1.01]

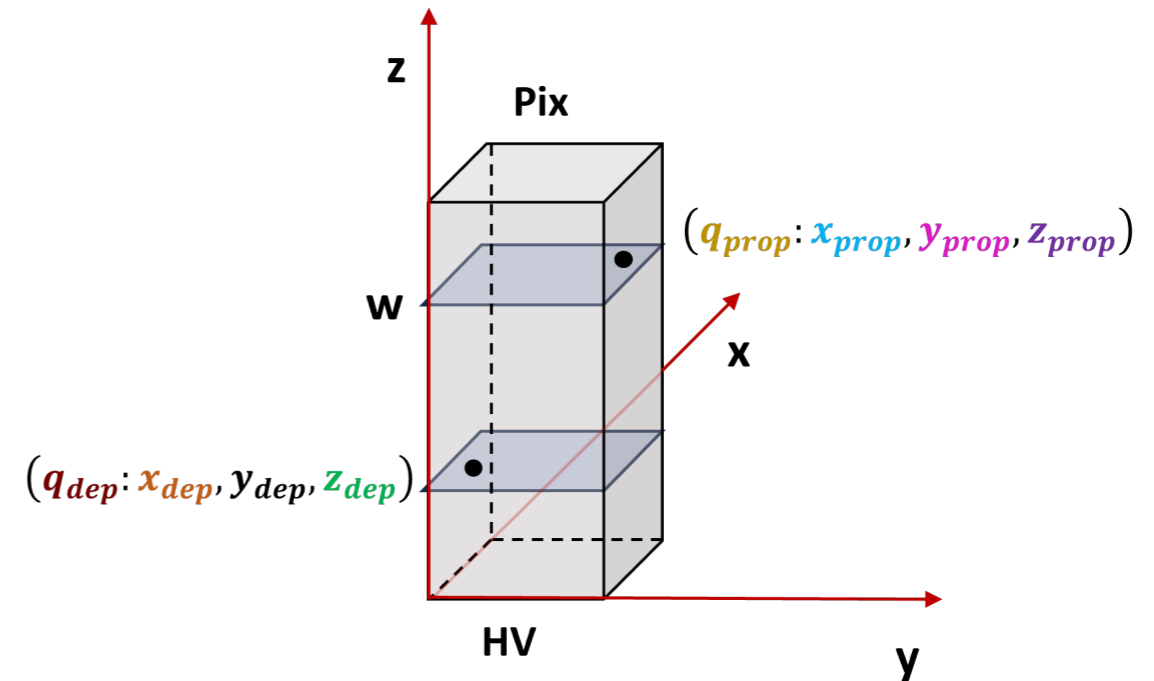
| Beam Divergence X, Y (mrad) | Cluster Size X(pix) | | |
|--------------------------------|---------------------|-------|---------|
| | FS | LUT | Rel err |
| 0,0 | 1.224 | 1.428 | 17 % |
| 10,0 | 1.344 | 1.449 | 8 % |
| 0,10 | 1.547 | 1.551 | 0.2% |
| 10,10 | 1.548 | 1.554 | 0.4% |

- Excellent agreement btw FS and LUT observed with beam divergence increased by 10 mrad along the Y-axis

ITk Pixel Radiation Damage Digitiser Speed Test

First tests in Athena

- Studies by Tomas Dado - Thanks!!
- Reminder - charge scaling and propagation :
 - ✦ $q_{prop} = CCE(z_{dep}) * q_{dep}(z_{dep})$
 - ✦ $z_{prop} = z_{dep} + \Delta z(z_{dep})$
 - ✦ $x_{prop} = x_{dep} + \tan(\theta_L)(z_{dep}) * \Delta z(z_{dep})$
- Performed first tests to determine the relative speed of the radiation damage digitiser for the planar ITk pixels using dummy LUTs (unirradiated detector)
 - ✦ No impact anticipated upon switching to LUTs for irradiated devices
- Initial tests indicates that the **radiation damage digitiser is as fast as standard digitiser**
 - ✦ Expectation: algorithm is the same, only additive and multiplicative corrections are applied



Summary

What next??

- Silicon detectors at hadron colliders are exposed to unprecedented levels of radiation damage
- Signal loss is the most important effect for cluster position determination
- Simulation of these effects in ATLAS MC for HL-LHC -> pixel reweighting
- Allpix-Squared together with TCAD simulations to make correction to take into account signal reduction and cluster shape changes
- Produced CCE vs Z , $\tan(\theta_L)$ vs Z and, ΔZ vs Z LUTs from Allpix-squared
- Validated the approach using closure tests: point charge depositions, line charge deposition, 120GeV Pions, Pions with $P_t = 100\text{GeV}$, 10 GeV and 1GeV at $\eta = 0, 1, \text{ and } 1.4$
- Similar efforts in progress for 3D (see [Jixing's talk](#)) and strip detectors
- Next steps :
 - ✦ Repeat the studies at different fluences and operating voltages ($1-3 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$, 300V - 500V)
 - ✦ Perform studies using planar sensors with pixel pitch of $25 \mu\text{m} \times 100 \mu\text{m}$, serving as further validation for the proposed technique
 - ✦ Anticipating the 2024 TB campaign for ITkPixV2 modules to validate our approach with the TB data

Thank you so much for your attention !! :)

Backup

ITk Pixel Radiation Damage Digitiser Speed Test

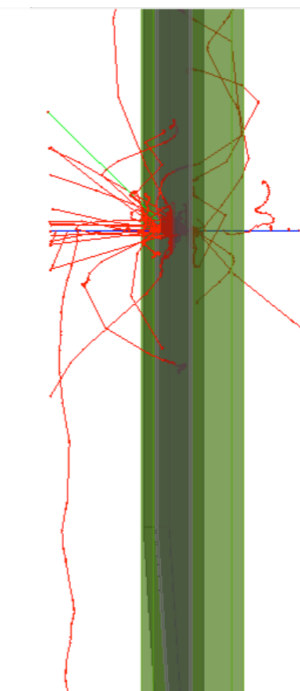
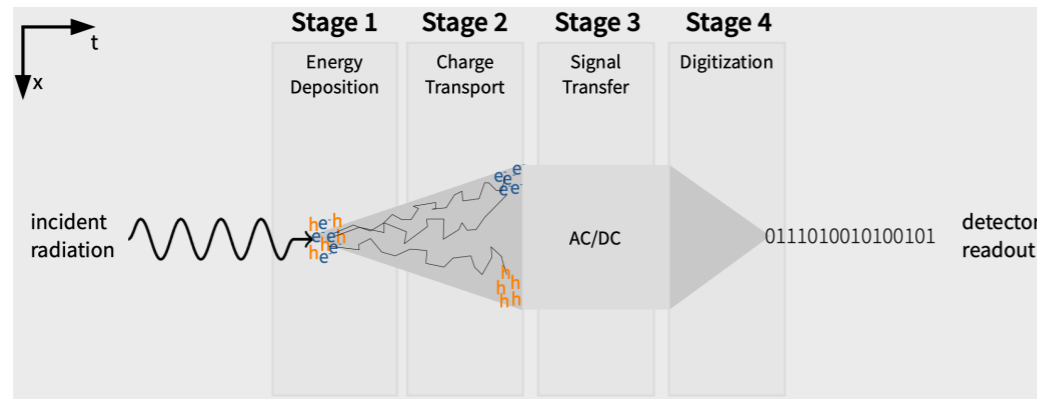
Comparison of Run2/3 strategy with the HL-LHC strategy

- Studies by Tomas Dado - Thanks!!
- Defining conventions :
 - ✦ D1: Standard digitiser (no radiation damage)
 - ✦ D2: Run 2/Run 3 radiation damage digitiser
 - ✦ D3: ITk radiation damage digitiser with LUTs
- Tests showed : $t(\mathbf{D3}) \sim t(\mathbf{D1})$ -> ITk radiation damage digitiser is as fast as the standard digitiser
- Tests also showed : $t(\mathbf{D2}) \sim 3 * t(\mathbf{D1})$ -> Run 2/Run 3 digitiser is **3 times slower** than standard digitiser
- Tentative conclusion : $t(\mathbf{D2}) \sim 3*t(\mathbf{D3})$ -> ITk radiation damage digitiser with LUTs is **3 times faster** than Run 2/Run 3 digitiser :)

Allpix-squared framework

Simulation flow

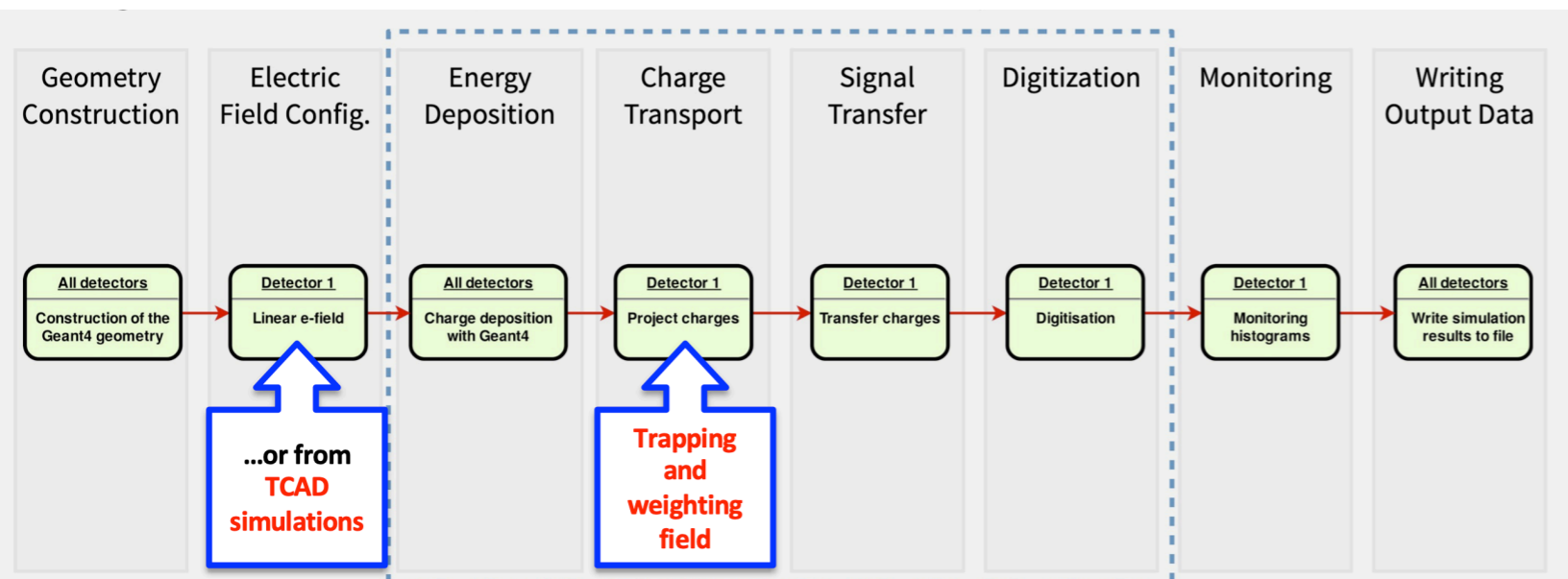
- Modular, generic simulation framework aiming at facilitating the different steps of the simulation of semiconductor detectors



- Visualization of an event in APSQ with 120 GeV π^+ (blue track) incident on an RD53A detector
- Red tracks: secondary electrons
- Green track: secondary photons

- Building blocks follow individual steps of signal formation in detector

<https://allpix-squared.docs.cern.ch/>



```
[Allpix]
log_level = "INFO"
log_format = "DEFAULT"
detectors_file = "planar_detector.conf"
number_of_events = 125000
root_file = "histos_125kEvents_100um_4e15_600V"
random_seed = 0

[GeometryBuilderGeant4]

[MagneticFieldReader]
model="constant"
magnetic_field = 0T 2T 0T

[DepositionPointCharge]
log_level = DEBUG
model = "scan"
source_type = "point"
number_of_charges = 1000
output_plots = 1

[ElectricFieldReader]
model = "mesh"
file_name = "../TCAD_files/EFieldIpxel_ElectricField_100um_600V_4e15.init"
output_plots = 1

[WeightingPotentialReader]
model = "mesh"
file_name = "../TCAD_files/flipped_mirrored_shifted_Ramo_Potential-3D-map-rd53a-50x50-100um_ElectrostaticPotential.init"
output_plots = 1

#For TCAD Efield
[TransientPropagation]
temperature = 253K
charge_per_step = 10
mobility_model = "canali"
trapping_model = "cmstracker"
fluence = 4e15/cm/cm
induction_matrix = 3 3
output_plots = 1

[PulseTransfer]
max_depth distance = 5um
output_plots = 1

[DefaultDigitizer]
output_plots = 1

[DetectorHistogrammer]

[ROOTObjectWriter]
file_name = "trees_125kEvents_100um_4e15_600V.root"
include = "MCTrack", "MCParticle", "PixelCharge", "PixelHit", "PropagatedCharge", "DepositedCharge"
```



Results of Pt = 100 GeV

Understanding trends

| Eta | Propagated X Position (mm) | | | Cluster Size Y(pix) | | | Cluster Size X(pix) | | | Cluster Charge (ke) | | |
|--------------------------------|----------------------------|---------|------------|---------------------|-------|---------|---------------------|-------|---------|---------------------|-------|---------|
| | FS | LUT | Diff/pitch | FS | LUT | Rel err | FS | LUT | Rel err | FS | LUT | Rel err |
| Normal incidence | 10 | 10 | 0 | 1.075 | 1.033 | 3.9% | 1.079 | 1.042 | 3.4% | 7.334 | 7.252 | 1.1% |
| 1 (theta_trk = 0.866Rad) | 10.01 | 10.01 | 0 | 3.011 | 3.013 | 0.07% | 1.243 | 1.424 | 14.5% | 10.39 | 10.68 | 2.8% |
| 1.4 (theta_trk = 1.088 Rad) | 10.0133 | 10.0207 | 14.8 % | 4.022 | 3.986 | 0.89% | 2.068 | 2.053 | 0.72% | 14.29 | 14.76 | 3.3% |

- Excellent agreement btw FS and LUT for PropagatedXPosition for eta = 0, 1 ; 15% difference observed at eta = 1.4
- Excellent agreement btw FS and LUT for cluster size y at different eta values
- Transverse cluster size (X) increases with higher eta values in both FS and LUT
 - ✦ Similar trend observed in ATLAS pixel data
 - ✦ Transverse cluster size \propto Longitudinal cluster size
- Excellent closure between FS and LUT for cluster charge at different eta values
 - ✦ Increasing eta -> particles incident at shallower angles, longer path length traversed in silicon, larger deposited charge , larger cluster charge

Results of Pt = 10 GeV

Understanding trends

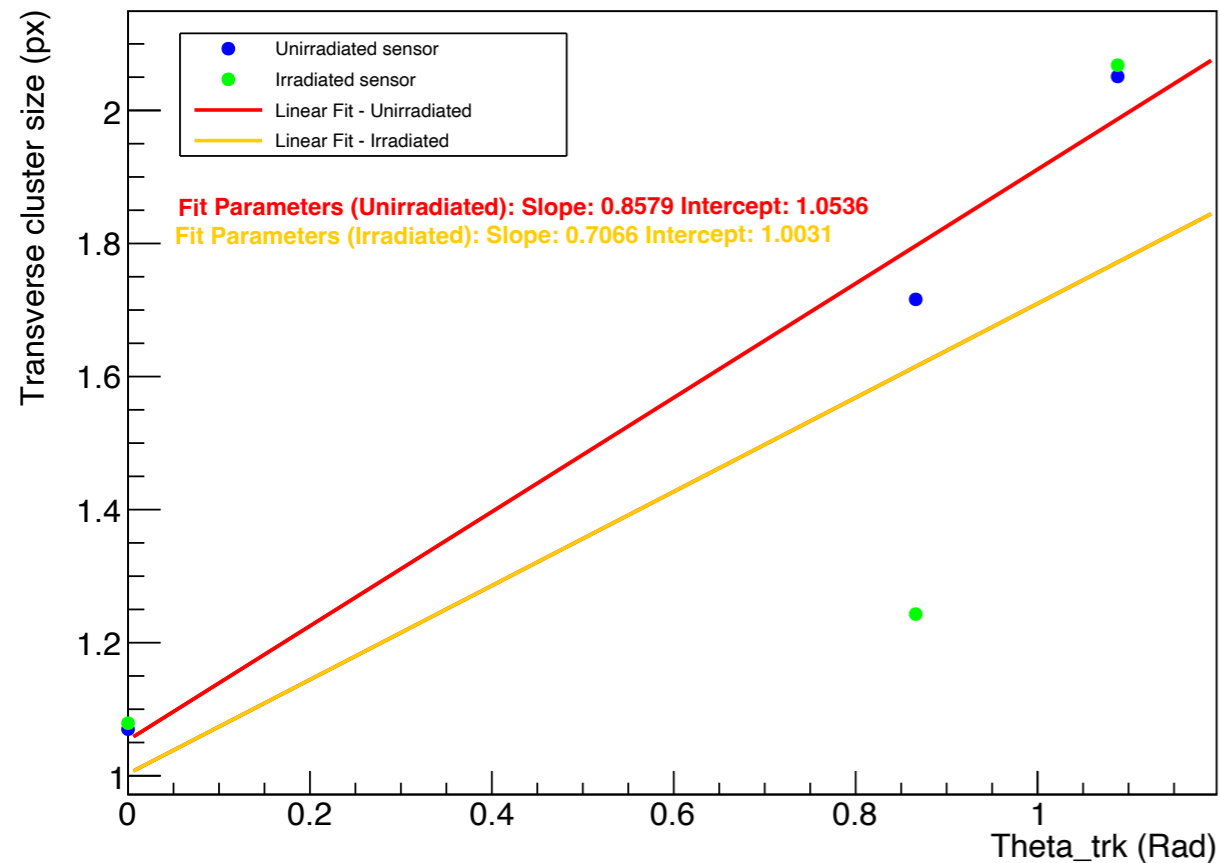
| Eta | Propagated X Position (mm) | | | Cluster Size Y(pix) | | | Cluster Size X(pix) | | | Cluster Charge (ke) | | |
|--------------------------------|----------------------------|---------|------------|---------------------|-------|---------|---------------------|-------|---------|---------------------|-------|---------|
| | FS | LUT | Diff/pitch | FS | LUT | Rel err | FS | LUT | Rel err | FS | LUT | Rel err |
| Normal incidence | 10.0020 | 10.0063 | 8.6% | 1.082 | 1.04 | 3.9% | 1.097 | 1.055 | 3.8% | 7.229 | 7.006 | 3.1% |
| 1 (theta_trk = 0.866Rad) | 10.0089 | 10.0155 | 4.6% | 3.023 | 2.988 | 1.2% | 1.217 | 1.422 | 16.8% | 10.37 | 10.95 | 5.6% |
| 1.4 (theta_trk = 1.088 Rad) | 10.0131 | 10.0154 | 4.6 % | 4.015 | 3.989 | 0.65% | 2.07 | 2.046 | 1.2% | 14.29 | 15.05 | 5.3% |

- Good agreement btw FS and LUT for PropagatedXPosition, relative difference < 10%
- Excellent agreement btw FS and LUT for cluster size y at different eta values
- Transverse cluster size (X) increases with higher eta values in both FS and LUT
 - ✦ Similar trend observed in ATLAS pixel data
 - ✦ Transverse cluster size \propto Longitudinal cluster size
- Good closure between FS and LUT for cluster charge at different eta values
 - ✦ Increasing eta -> particles incident at shallower angles, longer path length traversed in silicon, larger deposited charge , larger cluster charge

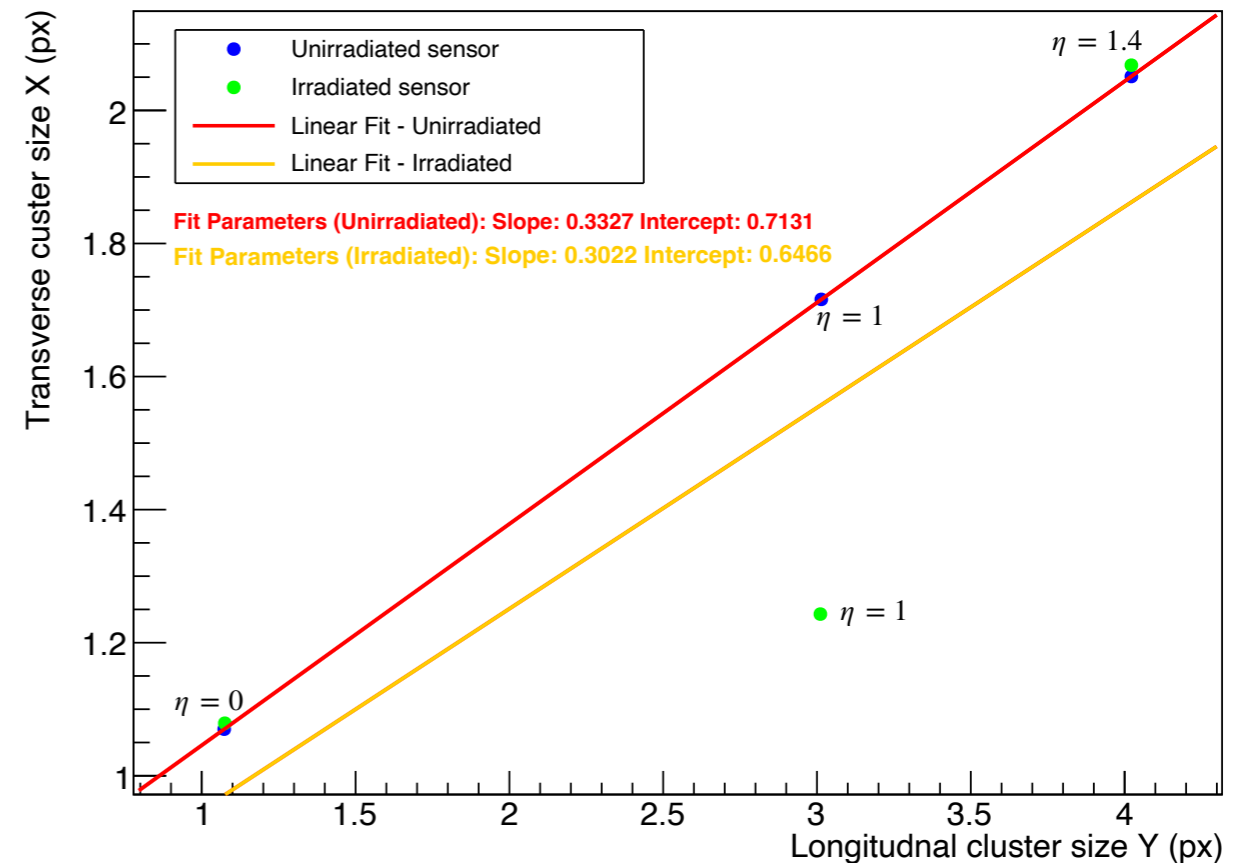
Understanding Transverse Cluster Size

100 GeV Pions, FS, Unirradiated vs Irradiated, -0.25Rad Y

Cluster size X vs θ_{trk}



Cluster size X vs Cluster size Y



- CSX at eta = 1 and eta = 1.4 very similar for irradiated and unirradiated sensors
- Significant differences seen at eta = 1

- CSX increases with increase in CSY for unirradiated and irradiated sensor -> similar trend seen in data
- $N_x \sim N_y * P_{\text{(sharing,x)}}$!!!
- Probability of sharing in the transverse plane for unirradiated sensors = 0.33